

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of Applicants: Date: February 27, 2008
Beaman et al. Group Art Unit: 2829
Serial No.: 09/251,988 Examiner: J. M. Hollington
Filed: February 17, 1999 Docket No.: YOR91999088US1
For: STRUCTURAL DESIGN AND PROCESSES TO CONTROL PROBE
POSITION ACCURACY IN A WAFER TEST PROBE ASSEMBLY

Amendment AF
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

In response to the Office Action dated December 21, 2008, please consider the following: